## Search Notes



Applicant(s)/Patent Under
Reexamination

10531397 KLOSTERS ET AL.

Examiner Art Unit

Flores, Leon 2611

## SEARCHED

Class	Subclass	Date	Examiner
375	354, 368	11/30/2007	LF
370	509, 510	11/30/2007	LF
327	141	11/30/2007	LF

## SEARCH NOTES

OLAKOII NOTEO		
Search Notes	Date	Examiner
Consulted with SPE David Payne in regards to the patentability of the claims.	12/11/2007	LF
Checked for possible double patenting.	11/29/2007	LF
Searched in EAST & NPL (IEEE).	11/30/2007	LF
Consulted with SPE David Payne in regards to the references used to reject the claims.	7/11/2008	LF
Consulted with SPE David Payne in regards to the arguments.	12/19/2008	LF

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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